

SLOVENSKI STANDARD oSIST prEN IEC 60539-1:2022

01-februar-2022

Neposredno ogrevani termistorji z negativnim temperaturnim koeficientom - 1. del: Splošna specifikacija

Directly heated negative temperature coefficient thermistors - Part 1: Generic specification

Direkt geheizte temperaturabhängige Widerstände mit negativem Temperaturkoeffizienten - Teil 1: Fachgrundspezifikation

Thermistances à coefficient de température négatif à chauffage direct - Partie 1: Spécification générique

oSIST prEN IEC 60539-1:2022

Ta slovenski standard je istoveten z: ai/ca prEN IEC 60539-1:2021

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ICS:

31.040.30 Termistorji Thermistors

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iTeh STANDARD PREVIEW (standards.iteh.ai)

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COMMITTEE DRAFT FOR VOTE (CDV)

	DATE OF CIRCULATION	N:	CLOSING DATE FOR VOTING:
	2021-11-26		2022-02-18
	SUPERSEDES DOCUM	ENTS:	
	40/2833/CD, 40/28	374/CC	
IEC TC 40: CAPACITORS AND RESISTORS F	OR ELECTRONIC EQUIP	MENT	
SECRETARIAT:		SECRETARY:	
Netherlands		Mr Ronald Drenth	en
OF INTEREST TO THE FOLLOWING COMMITTE	EES:	PROPOSED HORIZONTAL STANDARD: □	
i	Teh STA	Other TC/SCs are re in this CDV to the se	equested to indicate their interest, if any, ecretary.
FUNCTIONS CONCERNED:	ONMENT PREV	QUALITY ASSURAN	NCE SAFETY
SUBMITTED FOR CENELEC PARALLEL V	standard	NOT SUBMITTED F	OR CENELEC PARALLEL VOTING
Attention IEC-CENELEC parallel voting	9		
The attention of IEC National Comm CENELEC, is drawn to the fact that this Vote (CDV) is submitted for parallel voting	Committee Draft for	og/standards/sist/1	1e3aefca- -60539-1-
The CENELEC members are invited t CENELEC online voting system.	20		
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TITLE: Directly heated negative temperate	ure coefficient the	rmistors - Part 1:	Generic specification
PROPOSED STABILITY DATE: 2030			
NOTE FROM TC/SC OFFICERS:			

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INTERNATIONAL ELECTROTECHNICAL COMMISSION 276 277 278 DIRECTLY HEATED NEGATIVE TEMPERATURE 279 COEFFICIENT THERMISTORS -280 281 Part 1: Generic specification 282 283 **FOREWORD** 284 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising 285 286 all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international 287 co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, 288 Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with 289 290 291 may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for 292 293 Standardization (ISO) in accordance with conditions determined by agreement between the two organizations. 294 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international 295 consensus of opinion on the relevant subjects since each technical committee has representation from all 296 interested IEC National Committees. 297 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC 298 Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any 299 300 misinterpretation by any end user. 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications 301 302 transparently to the maximum extent possible in their national and regional publications. Any divergence between 303 any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter. 304 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any 305 services carried out by independent certification bodies. 306 307 6) All users should ensure that they have the latest edition of this publication, 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or 308 309 310 other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, of reliance upon, this IEC Publication or any other IEC 311 312 313 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is 314 indispensable for the correct application of this publication. 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent 315 rights. IEC shall not be held responsible for identifying any or all such patent rights. 316 International Standard IEC 60539-1 has been prepared by IEC technical committee 40: 317 Capacitors and resistors for electronic equipment. 318 This fourth edition cancels and replaces the third edition published in 2016 and constitutes a 319 technical revision. 320 This edition includes the following significant technical changes with respect to the previous 321 edition: 322 - Restructured completely to comply to ISO/IEC directives; categorization and reorganization of test 323 methods into these categories; 324 - Annex X added for comparison to previous edition 325 - Some wordings, figures and references have been revised. 326

The text of this International Standard is based on the following documents:

FDIS	Report on voting
XX/XX/FDIS	XX/XX/RVD

- Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.
- This document has been drafted in accordance with the ISO/IEC Directives, Part 2.
- The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to
- the specific document. At this date, the document will be
- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- 338 amended.

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340	DIRECTLY HEATED NEGATIVE TEMPERATURE
341	COEFFICIENT THERMISTORS -
342	
343	Part 1: Generic specification
344	
345	1 Scope
346 347	This part of IEC 60539 is applicable to directly heated negative temperature coefficient thermistors, typically made from transition metal oxide materials with semiconducting properties
348 349	It establishes standard terms, inspection procedures and methods of test for use in sectiona and detail specifications of electronic components for quality assessment or any other purpose.
350	2 Normative references
351 352 353 354	The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.
355	IEC 60062, Marking codes for resistors and capacitors ARD
356	IEC 60068-1:2013, Environmental testing – Part 1: General and guidance
357	IEC 60068-2-1, Environmental testing - Part 2-1: Tests - Tests A. Cold
358	IEC 60068-2-2, Environmental testing – Part 2-2: Tests – Tests B: Dry heat oSIST prEN IEC 60539-1:2022
359	IEC 60068-2-6, Environmental testing en Rart 2:6: Tests at Test Fc Vibration (sinusoidal)
360	3a80-4cca-92e3-eb228fc0c459/osist-pren-iec-60539-1- IEC 60068-2-11, Environmental testing procedures – Part 2-11: Tests – Test Ka: Salt mist
361	IEC 60068-2-14, Environmental testing – Part 2-14: Tests – Test N: Change of temperature
362	IEC 60068-2-17, Basic environmental testing procedures – Part 2-17: Tests – Test Q: Sealing
363 364	IEC 60068-2-20, Environmental testing — Part 2-20: Tests — Test T: Test methods for solderability and resistance to soldering heat of devices with leads
365 366	IEC 60068-2-21, Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices
367	IEC 60068-2-27, Environmental testing – Part 2-27: Tests – Test Ea and guidance: Shock
368 369	IEC 60068-2-31, Environmental testing – Part 2-31: Tests – Test Ec: Rough handling shocks, primarily for equipment-type specimens
370 371	IEC 60068-2-38, Environmental testing – Part 2-38: Tests – Test Z/AD: Composite temperature/humidity cyclic test
372 373 374	IEC 60068-2-45:1980, Basis Environmental testing procedures – Part 2-45: Tests – Test XA and guidance: Immersion in cleaning solvents IEC 60068-2-45:1980/AMD1:1993

- 375 IEC 60068-2-52, Environmental testing Part 2-52: Tests Test Kb: Salt mist, cyclic (sodium
- 376 chloride solution)
- 377 IEC 60068-2-54, Environmental testing Part 2-54: Tests Test Ta: Solderability testing of
- 378 electronic components by the wetting balance method
- 379 IEC 60068-2-58, Environmental testing Part 2-58: Tests Test Td: Test methods for
- solderability, resistance to dissolution of metallization and to soldering heat of surface mounting
- 381 devices (SMD)
- 382 IEC 60068-2-69, Environmental testing Part 2-69: Tests Test Te: Solderability testing of
- 383 electronic components for surface mounting devices (SMD) by the wetting balance method
- 384 IEC 60068-2-78, Environmental testing Part 2-78: Tests Test Cab: Damp heat, steady state
- 385 IEC 60294, Measurement of the dimensions of a cylindrical component with axial terminations
- 386 IEC 61193-2, Quality assessment systems Part 2: Selection and use of sampling plans for
- inspection of electronic components and packages
- 388 IEC 60717, Method for the determination of the space required by capacitors and resistors with
- 389 unidirectional terminations
- 390 IEC 61249-2-7, Materials for printed boards and other interconnecting structures Part 2-7:
- Reinforced base materials clad and unclad Epoxide woven E-glass laminated sheet of defined
- flammability (vertical burning test), copper-clad

3 Terms and definition (standards.iteh.ai)

For the purposes of this document, the following terms and definitions apply.

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395 **3.1**

393

- https://standards.iteh.ai/catalog/standards/sist/1e3aefca-
- group of products having similar design features manufactured by the same techniques and
- falling within the manufacturer's usual range of ratings for these products
- 399 Note 1 to entry: Mounting accessories are ignored, provided they have no significant effect on the test results.
- 400 Note 2 to entry: Ratings cover the combination of
- 401 electrical ratings,
- 402 sizes, and
- 403 climatic category.
- 404 Note 3 to entry: The limits of the range of ratings should be given in the detail specification.
- 405 **3.2**
- 406 style
- variation within a type having specific nominal dimensions and characteristics
- 408 3.3
- 409 thermistor
- 410 thermally sensitive semiconducting resistor whose primary function is to exhibit an important
- change in electrical resistance with a change in body temperature
- 412 **3.4**
- 413 negative temperature coefficient thermistor
- 414 NTC thermistor
- 415 thermistor in which the resistance decreases with increasing temperature
- 416 Note 1 to entry: In general, the term 'NTC thermistor' is used.

- 417 3.5
- 418 directly heated negative temperature coefficient thermistor
- thermistor which obtains its resistance variation by the changes of physical conditions.
- 420 Note 1 to entry: Physical conditions include the current through the thermistor, ambient temperature, humidity, wind
- 421 velocity, gas, etc.
- 422 3.6
- indirectly heated negative temperature coefficient thermistor
- 424 thermistor which obtains its resistance variation primarily by the change of temperature of the
- 425 thermistor, due to the change of a current through a separate heater which is in close contact
- with, but electrically insulated from, the thermistor element
- 427 Note 1 to entry: The temperature of the thermistor can also be changed by the changes of physical conditions such
- 428 as current through the thermistor element itself, ambient temperature, humidity, wind velocity, gas, etc.
- 429 Note 2 to entry: This term is for information only.
- 430 3.7
- 431 positive temperature coefficient thermistor
- 432 PTC thermistor
- thermistor in which the resistance increases with increasing temperature
- Note 1 to entry: In general, the term 'PTC thermistor' is used.
- 435 Note 2 to entry: This term is for information only.
- 436 **3.8**
- NTC thermistor with wire terminations EVEV
- NTC thermistor provided with wire terminations

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- **4**39 **3.9**
- 440 NTC thermistor without wire terminations
- thermistor provided only with two metallized faces to be used as electrical contacts

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- Note 1 to entry: This term is for information only 28 fc0c459/osist-pren-iec-60539-1-
- 443 **3.10** 2022
- 444 insulated thermistor
- NTC thermistor coated with materials such as resin, glass or ceramic, capable of meeting the
- 446 requirements of the insulation resistance and voltage proof tests when specified in the test
- 447 schedule
- 448 **3.11**
- 449 non-insulated NTC thermistor
- 450 NTC thermistor with or without coating materials for surfacing of elements but not intended to
- 451 meet the requirements of the insulation resistance and voltage proof tests when specified in the
- 452 test schedule
- **3.12**
- 454 surface mount NTC thermistor
- NTC thermistor whose small dimensions and nature or shape of terminations make it suitable
- 456 for use in hybrid circuits and on printed board
- 457 **3.13**
- 458 assembled NTC thermistor
- 459 **probe**
- 460 NTC thermistor encapsulated in different materials such as tubes, plastic and metal housing
- and/or assembled with cables and/or connectors
- Note 1 to entry: This term is for information only.

463 **3.14**

464 NTC thermistor for sensing

- thermistor which responds to temperature changes and therefore is used for temperature
- 466 sensing and control
- 467 **3.15**
- 468 inrush current limiting NTC thermistor
- NTC thermistor which limits the inrush current just after switching on the power
- 470 **3.16**
- 471 residual resistance
- 472 <inrush current-limiting thermistors> value of the d.c. resistance of a thermistor when its thermal
- 473 stability is reached with the maximum current passing
- Note 1 to entry: This term is for information only.
- 475 **3.17**
- 476 maximum permissible capacitance
- 477 <inrush current-limiting NTC thermistors> maximum permissible capacitance value of a
- capacitor which can be connected to a thermistor under loading
- 479 **3.18**

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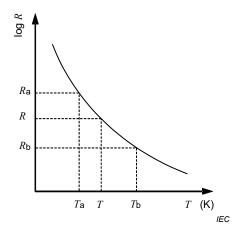
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- 480 zero-power resistance
- 481 R_T ileh STANDARD
- value of the d.c. resistance of a thermistor, when measured at a specified temperature, under
- such conditions that the change in resistance due to the internal generation of heat is negligible
- with respect to the total error of measurement
 - 3.19 (standards.iteh.ai)
- 486 nominal zero-power resistance
- nominal value of zero-power resistance at the standard reference temperature of 25 °C, unless
- 488 otherwise specified <u>oSIST prEN IEC 60539-1:2022</u>

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- **3.20** 3a80-4cca-92e3-eb228fc0c459/osist-pren-iec-60539-1-
- 490 **resistance-temperature characteristic**491 relationship between the zero-power resistance
 - relationship between the zero-power resistance and the body temperature of a thermistor
- 493 Note 1 to entry: Typical resistance-temperature characteristic for NTC thermistors is shown in Figure 1.



495 NOTE Slightly downward convexed curve when the temperature range is large.

Figure 1 – Typical resistance-temperature characteristic for NTC thermistors

Note 2 to entry: The resistance law follows approximately the formula: